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APPLICATION NO. FILING DATE		G DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO	
10/667,879 09/22/2003		2/2003	Gordhan Barevadia	TI-36281	1157	
23494	7590 01/24/2006			EXAMINER		
		TS INCORPOR	CHUNG, PHUNG M			
DALLAS, 7	5474, M/S 39 TX - 75265	199		ART UNIT	PAPER NUMBER	
,				2138		

DATE MAILED: 01/24/2006

Please find below and/or attached an Office communication concerning this application or proceeding.

······		Applica	tion No.	Applicant(s)						
Office Action Summary			379	BAREVADIA ET AL.						
			ər	Art Unit						
		-	ly Chung	2138						
Period fo	The MAILING DATE of this commun or Reply	ication appears on ti	ne cover sheet with the c	orrespondence ad	ldress					
WHIC - Exter after - If NO - Failu Any	ORTENED STATUTORY PERIOD FOR CHEVER IS LONGER, FROM THE MISSIONS OF TIME IN THE MISSION OF THE M	AILING DATE OF 7 of 37 CFR 1.136(a). In no equinication. attrory period will apply and will, by statute, cause the apply and the statute of the statute o	THIS COMMUNICATION went, however, may a reply be time will expire SIX (6) MONTHS from polication to become ABANDONE	N. nely filed the mailing date of this c D (35 U.S.C. § 133).						
Status										
1)	Responsive to communication(s) file	d on .								
2a)□										
3)□	<i>,</i> —									
	closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.									
Dispositi	on of Claims									
4)🖂	4) Claim(s) <u>1-14</u> is/are pending in the application.									
	4a) Of the above claim(s) is/are withdrawn from consideration.									
5)🖂	Claim(s) <u>1-9</u> is/are allowed.									
6)⊠	Claim(s) 10-14 is/are rejected.									
7)	Claim(s) is/are objected to.									
8)□	8) Claim(s) are subject to restriction and/or election requirement.									
Applicati	on Papers									
9)	The specification is objected to by the	e Examiner.								
10)⊠ The drawing(s) filed on <u>22 September 2003</u> is/are: a)□ accepted or b)⊠ objected to by the Examiner.										
	Applicant may not request that any object	ction to the drawing(s)	be held in abeyance. See	e 37 CFR 1.85(a).						
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).										
11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.										
Priority ι	ınder 35 U.S.C. § 119									
12)☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a)☐ All b)☐ Some * c)☐ None of:										
	1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No									
	3. Copies of the certified copies of the priority documents have been received in this National Stage									
	application from the International Bureau (PCT Rule 17.2(a)).									
* See the attached detailed Office action for a list of the certified copies not received.										
Attachmen	• •									
	e of References Cited (PTO-892) e of Draftsperson's Patent Drawing Réview (P	TO-948)	4) Interview Summary Paper No(s)/Mail Da							
3) 🔲 Inforr	e of Dransperson's Patent Drawing Review (P nation Disclosure Statement(s) (PTO-1449 or r No(s)/Mail Date			nal Patent Application (PTO-152)						

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## 1. Drawing:

The Figure should be changed to - - Figure 1 - -.

2. Claims 10-14 are objected to because the method steps, for example:

Monitoring scan automatic test pattern... (ATPG) and (BIST) patterns...;

Selecting desired scan chain outputs...;

Combining the die ID scan out signal m memory BIST signals and scan chains signals...;

Generating the monitored IC output signals;

Configuring a burn-in configuration register;

Combining IC Die identification (ID) scan out data...; and

Combining memory BIST fail/go-nogo status data...,

should have a flow chart or flow diagram showing these method steps or these features should be canceled from the claims.

#### Claim Rejections - 35 USC § 112

3. Claims 10-14 are rejected under 35 U.S.C. 112, second paragraph, as being indefinite for failing to particularly point out and distinctly claim the subject matter which applicant regards as the invention.

As per claim 10, lines 3-6, "monitoring scan automatic test pattern generation (ATPG) and memory built-in self-test (BIST patterns... to generate monitored IC output signals" the relationship between the monitoring step and the selecting step is unclear; and

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Line 5, "desired scan chain outputs and memory BIST status outputs" does not have a clear antecedent basis. Appropriate correction is required.

As per claims 11-14, these claims are rejected because they dependent upon the rejected base claim.

### Claim Rejections - 35 USC § 102

4. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless –(e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.

5. Claim 10 is rejected under 35 U.S.C. 102(e) as being anticipated by Balachandran et al (US-2003/0149913).

Balachandran et al disclose a method of observing integrated circuit failures during burn-in testing, comprising the steps of:

Monitoring scan automatic test pattern generation and meory built-in self-test patterns. And

Selecting desired scan chain outputs and memory BIST outputs to generate monitored IC output signals. (See Fig. 8, paragraphs (0037)-(0040).

The applied reference has a common assignee Texas Instruments Incorporated with the instant application. Based upon the earlier effective U.S. filing date of the reference, it constitutes prior art under 35 U.S.C. 102(e). This rejection under 35 U.S.C. 102(e) might be overcome either by a showing under 37 CFR 1.132 that any invention

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disclosed but not claimed in the reference was derived from the inventor of this application and is thus not the invention "by another," or by an appropriate showing under 37 CFR 1.131.

### Allowable Subject Matter

6. Claims 1-9 are allowable.

#### Reason for Allowance

7. The following is an examiner's statement of reasons for allowance: Claims 1-9 are allowable over the arts of record. This is because the art of record does not disclose or teach the invention as recited in claims 1 and 4, and including:

A burn-in configuration register;

A combinational logic operational in response to IC Die identification (ID) scan data and burn-in configuration register data to generate Die ID scan out signals;

A means for generating memory BIST signals;

A means for generating scan chain signals; and

An exclusive-OR logic operational in response to the Die ID scan out signals, memory BIST signals, and scan chains signals to generate monitored output signals.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

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8. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Phung My Chung whose telephone number is 571-272-3818. The examiner can normally be reached on Monday to Friday.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Albert Decady can be reached on 571-272-3819. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Phung\My\Chung

Primary Patent Examiner

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